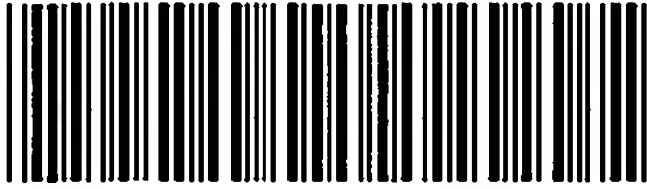


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/642,955	MIKAWA ET AL.	
	Examiner	Art Unit	
	Jack Chen	2813	

SEARCHED			
Class	Subclass	Date	Examiner
438	3, 239, 240, 250, 393	5/11/2005	JC

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
east	5/11/2005	JC